

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/642,643	TANAKA ET AL.	
		Examiner	Art Unit	Page 1 of 2
		Colleen P. Cooke	1754	

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	C	US-2005/0074220	04-2005	Rey, Christopher Mark	385/141
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	N	WO 2004/048292 A1	06-2004	PCT	SUPLINSKAS, Raymond J.	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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